## Comparison on the atomic and electronic structures of crystalline and amorphous Zn<sub>2</sub>SnO<sub>4</sub> using density functional theory

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Zinc Tin oxide (ZTO) is one of the promising n-type oxide semiconductors which is used as the channel layers for various electronic devices. [1] It is usually used as amorphous film due to uniform deposition without grain boundary. In addition, the ternary oxide system has higher crystallization temperature of 600 °C, so the temperature window for using stable amorphous film is wider than binary oxides which have lower crystallization temperature. The mobility of amorphous film is reported as  $\sim$  10 times higher than that of amorphous Si. [2] However, compared to polycrystalline phase, the mobility of amorphous state is lower. In this study, we investigated the differences among crystalline and amorphous zinc tin oxide in the atomic and electronic structure.

Calculations based on the density functional theory were performed using VASP code. Crystalline phase of  $Zn_2SnO_4$  (c- $Zn_2SnO_4$ ) in the inverse spinel structure was used. Amorphous  $Zn_2SnO_4$  (a- $Zn_2SnO_4$ ) structure was obtained by melt-quenching method based on the first principles molecular dynamics. For atomic structure analysis, radial distribution function (RDF) was used for bond lengths and coordination numbers (CNs). The RDF was obtained by averaged atomic positions which were obtained during annealing at 300 K for 1 ps. For electronic structure analysis, projected density-of-states (PDOS) and inverse participation ratio (IPR) were used.

Fig. 1(a) shows the RDF of O-Zn for c-Zn<sub>2</sub>SnO<sub>4</sub> and a-Zn<sub>2</sub>SnO<sub>4</sub>. The RDF was used in order to count the average bond lengths and CNs of cations. The average bond length of O-Zn obtained by RDF of c-Zn<sub>2</sub>SnO<sub>4</sub> is longer than that of a-Zn<sub>2</sub>SnO<sub>4</sub>. The CN of c-Zn<sub>2</sub>SnO<sub>4</sub> was 5, which resulted from the half of tetrahedra (4) and the other half of octahedra (6) bonds with oxygens. However, the CN of a-Zn<sub>2</sub>SnO<sub>4</sub> is 4.43 which decreased from that of c-Zn<sub>2</sub>SnO<sub>4</sub>. Zn atoms in a-Zn<sub>2</sub>SnO<sub>4</sub> form tetrahedra or bi-pyramid bonds with oxygens. Fig. 1(b) shows the RDF of O-Sn for c-Zn<sub>2</sub>SnO<sub>4</sub> and a-Zn<sub>2</sub>SnO<sub>4</sub>. The average bond length of O-Sn of c-Zn<sub>2</sub>SnO<sub>4</sub> is almost similar as that of a-Zn<sub>2</sub>SnO<sub>4</sub>. The cNs of c-Zn<sub>2</sub>SnO<sub>4</sub> and a-Zn<sub>2</sub>SnO<sub>4</sub> were almost the same as 6, and 5.89, respectively. It means the high crystallization temperature is resulted from the lowered CN and shortened bond length of Zn-O.

Fig. 2(a) and 2(b) show the IPR and PDOS for  $c-Zn_2SnO_4$  and  $a-Zn_2SnO_4$ . Zn 3d-O 2p hybridized orbital mainly forms the valence band maximum and Sn 5s forms the conduction band minimum. Despite of different local structure, the PDOS between tetrahedral and octrahedral Zn were not different each other in  $c-Zn_2SnO_4$ . Lower IPR value as 1/N means fully delocalized states to N atoms, on the other hand, higher IPR value means localized states. The IPR value at the valence band maximum in  $a-Zn_2SnO_4$  is much higher than that in  $c-Zn_2SnO_4$ . Especially, the interactions between O-2p in the

valence band maximum in  $a-Zn_2SnO_4$  were dominant and they form the long valence band tail which exists as localized at the ~ 1 eV region. In addition, the conduction band minimum also showed localized states in  $a-Zn_2SnO_4$ . The calculation results correspond to the experimental reports related to the wide valence band tail and lower electronic mobility in amorphous structure. [3,4]

References

- [1] J. Lee et al., J. Mater. Chem. C. 1 (2013) 6364.
- [2] K. Nomura et al., Nature 432 (2004) 488.
- [3] J. Lee et al., Appl. Phys. Lett. 102 (2013) 242111.
- [4] P. T. Erslev et al., Appl. Phys. Lett. 95 (2009) 192115.



FIG. 1. The radial distribution functions of (a) O-Zn and (b) O-Sn of  $c-Zn_2SnO_4$  and  $a-Zn_2SnO_4$  obtained during the first principles molecular dynamics at 300 K.



FIG. 2. The IPRs and PDOSs for (a)  $c-Zn_2SnO_4$  and (b)  $a-Zn_2SnO_4$ . The conduction band for the PDOS was five times multiplied for better viewing. Black, Red, Blue lines indicate the s, p, and d-orbitals for the PDOS.